P/N: 108-011
Pitch: 150 μm - 3000 μm
Configuration: GS, SG
All of the above specifications are based on an overtravel (downward movement of probe after initial touchdown on the substrate) of 100-150 μm. This amount of overtravel can be set before calibration on the Impedance Standard Substrate (ISS) using the alignment marks (allows precise setting of probe separation and overtravel). Figure 1 shows that initial contact with the edge of the probe tips should be made at reference plane X (midpoint between the outer flat edge and the internal apex). The desired overtravel and thus skate (forward movement of probe tips after initial contact with substrate) is then achieved by adjusting the Z height on the positioner to move the edge of the probe tips to reference plane Y (midpoint between the internal apex and the flag points). This can also be seen from the photographic images shown in Figure 2.

Figure 1: Alignment marks

Figure 2: Images showing correct alignment and placement of probe tips

Calibration Coefficients are dependent on the probe tip configuration, placement on a standard, and the standard configurations. This leads to unique calibration coefficients for a unique pair of probe and ISS. Therefore, the calibration coefficients are supplied with the probe not with the ISS.